

Amendments to the Specification

Please replace the paragraph beginning at page 5, line 10, with the following rewritten paragraph:

The invention will be described in detail according to the enclosed drawings, where:

Fig. 1 shows the preferred embodiment of the secondary electron detector fitted with the KAPTON® diaphragm according to the present invention, in the specimen chamber of the electron microscope;

Fig. 2 shows another preferred embodiment of the secondary electron detector with a copper grid, according to the present invention, also in the specimen chamber of the electron microscope;

Fig. 3 shows the sectional view of the KAPTON® diaphragm used in the first exemplified embodiment of the detector according to this invention; [[and]]

Fig. 4 shows a preferred embodiment of the secondary electron detector with a metallic disk, according to the present invention, also in the specimen chamber of the electron microscope; and

Fig. 5 shows another exemplary embodiment of the detector according to this invention.